Applicant(s)/Patent Under Reexamination Application/Control No. 10/712,356 JUNG ET AL. Notice of References Cited Art Unit Examiner Page 1 of 1 2861 Shih-wen Hsieh **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-			
	В	US-			
	С	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	-	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	EP 1 153 749 A1	11-2001	Europe	Steinfield et al.	
	0					
	Р					
	Q					
	R					<u> </u>
	s					
	Т					

NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	υ				
	٧				
	w				
	x				

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.